

### **Defect-oriented test generation and fault simulation in the environment of MOSCITO**

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### **Digital design flow with test activities**

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### **FPGA design flow with automated test generation**

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### **High-level synthesis and test in the MOSCITO-based virtual laboratory**

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### **Integration of digital test tools to the internet-based environment MOSCITO**

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### **Internet-based testability-driven test generation in the virtual environment MOSCITO**

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### **Virtual laboratory for research in dependable microelectronics**

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